Form 1449 (Modified)  Information Disclosure  Statement By Applicant	Atty Docket No. GENSP014 Applicant:	Application No.: 10/726,802
(Use Several Sheets if Necessary)	Kobayashi Filing Date December 2, 2003	Group 2181

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Examiner	ı			- ocuments			
Initial	No.	Patent No.	Date	Patentee	-	Sub-	Filing
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Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date			Sub-	Trans	
	B1.		Date	Patent Office	Class	class	Yes	No
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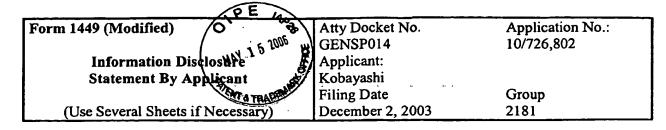
Other Documents

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CKL	C1.	Examination Report dated March 15, 2006 from European Patent Application No. 04255610.0.
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